

→ HF-100DCA Life-time measurement system for silicon bulks/ingots by JIS method



Selling Points

Global standard model for the lifetime test of silicon bulk
JIS direct current anodizing method
Data processing by digital oscilloscope and PC with software

Details

Applications

Silicon ingot, Silicon bulk, Prismatic shape (JIS code)

Sample sizes

*Please contact us in details

Measuring range

50 μ S~ 20mS

